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LIST OF	KEFE	RENCES CITED BY A	PPLICANT	Naoyoshi HATAKEYAMA, et al.		100 0000		
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U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE		
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT DATE COUNTRY			TRANSLATION			
		NUMBER	DATE			YES NO		
/YV/	AO	2000 122295	04/28/00	JP (English abstract only and equivalent of US 6 391 520)			NO	
/YV/	AP	2001 240625	09/04/01	JP (English abstract only)			NO	
/YV/	AQ	2001 048931	02/20/01	JP (English abstract only and equivalent of EP 1 172 384)			NO	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
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	AZ				Additional References sheet(s) attached			
Examiner	Examiner /Yevgeny Valenrod/					Date Considered 12/05/2008		
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